

SEMiX402GAR066HDs



SEMiX® 2s

Trench IGBT Modules

SEMiX402GAR066HDs

Features

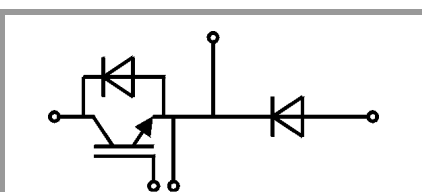
- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$ with positive temperature coefficient
- UL recognised file no. E63532

Typical Applications*

- Matrix Converter
- Resonant Inverter
- Current Source Inverter

Remarks

- Case temperature limited to $T_C=125^\circ\text{C}$ max.
- Product reliability results are valid for $T_j=150^\circ\text{C}$
- For short circuit: Soft R_{Goff} recommended
- Take care of over-voltage caused by stray inductance



GAR

Absolute Maximum Ratings				
Symbol	Conditions		Values	Unit
IGBT				
V_{CES}	$T_j = 25^\circ\text{C}$		600	V
I_C	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	502	A
		$T_c = 80^\circ\text{C}$	379	A
I_{Cnom}			400	A
I_{CRM}	$I_{CRM} = 2 \times I_{Cnom}$		800	A
V_{GES}			-20 ... 20	V
t_{psc}	$V_{CC} = 360\text{ V}$	$T_j = 150^\circ\text{C}$	6	μs
	$V_{GE} \leq 15\text{ V}$			
	$V_{CES} \leq 600\text{ V}$			
T_j			-40 ... 175	$^\circ\text{C}$
Inverse diode				
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	543	A
		$T_c = 80^\circ\text{C}$	397	A
I_{Fnom}			400	A
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$		800	A
I_{FSM}	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$		1800	A
T_j			-40 ... 175	$^\circ\text{C}$
Freewheeling diode				
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	566	A
		$T_c = 80^\circ\text{C}$	412	A
I_{Fnom}			400	A
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$		800	A
I_{FSM}	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$		1800	A
T_j			-40 ... 175	$^\circ\text{C}$
Module				
$I_{t(RMS)}$	$T_{terminal} = 80^\circ\text{C}$		600	A
T_{stg}			-40 ... 125	$^\circ\text{C}$
V_{isol}	AC sinus 50Hz, $t = 1\text{ min}$		4000	V

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
IGBT						
$V_{CE(sat)}$	$I_C = 400\text{ A}$ $V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$	1.45	1.85		V
		$T_j = 150^\circ\text{C}$	1.7	2.1		V
V_{CE0}		$T_j = 25^\circ\text{C}$	0.9	1		V
		$T_j = 150^\circ\text{C}$	0.85	0.9		V
r_{CE}	$V_{GE} = 15\text{ V}$	$T_j = 25^\circ\text{C}$	1.4	2.1		$\text{m}\Omega$
		$T_j = 150^\circ\text{C}$	2.1	3.0		$\text{m}\Omega$
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 6.4\text{ mA}$		5	5.8	6.5	V
I_{CES}	$V_{GE} = 0\text{ V}$ $V_{CE} = 600\text{ V}$	$T_j = 25^\circ\text{C}$	0.15	0.45		mA
		$T_j = 150^\circ\text{C}$				mA
C_{ies}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$		24.7		nF
C_{oes}		$f = 1\text{ MHz}$		1.54		nF
C_{res}		$f = 1\text{ MHz}$		0.73		nF
Q_G	$V_{GE} = -8\text{ V...} + 15\text{ V}$			3200		nC
R_{Gint}	$T_j = 25^\circ\text{C}$			1.00		Ω

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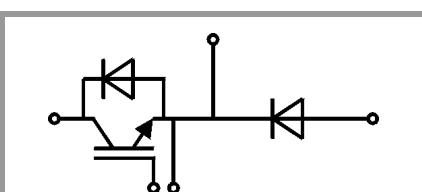
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Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
$t_{d(on)}$	$V_{CC} = 300\text{ V}$	$T_j = 150^\circ\text{C}$		150		ns
t_r	$I_C = 400\text{ A}$	$T_j = 150^\circ\text{C}$		125		ns
E_{on}	$V_{GE} = \pm 15\text{ V}$	$T_j = 150^\circ\text{C}$		22		mJ
$t_{d(off)}$	$R_{G\ on} = 4.5\ \Omega$	$T_j = 150^\circ\text{C}$		900		ns
t_f	$R_{G\ off} = 4.5\ \Omega$	$T_j = 150^\circ\text{C}$		65		ns
E_{off}		$T_j = 150^\circ\text{C}$		24		mJ
$R_{th(j-c)}$	per IGBT				0.12	K/W
Inverse diode						
$V_F = V_{EC}$	$I_F = 400\text{ A}$	$T_j = 25^\circ\text{C}$		1.4	1.60	V
	$V_{GE} = 0\text{ V}$ chip	$T_j = 150^\circ\text{C}$		1.4	1.6	V
V_{F0}		$T_j = 25^\circ\text{C}$	0.9	1	1.1	V
		$T_j = 150^\circ\text{C}$	0.75	0.85	0.95	V
r_F		$T_j = 25^\circ\text{C}$	0.8	1.0	1.3	m Ω
		$T_j = 150^\circ\text{C}$	1.1	1.4	1.6	m Ω
I_{RRM}	$I_F = 400\text{ A}$	$T_j = 150^\circ\text{C}$		250		A
Q_{rr}	$di/dt_{off} = 3700\text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$		47		μC
E_{rr}	$V_{GE} = -8\text{ V}$	$T_j = 150^\circ\text{C}$		10		mJ
	$V_{CC} = 300\text{ V}$	$T_j = 150^\circ\text{C}$				
$R_{th(j-c)}$	per diode				0.15	K/W
Freewheeling diode						
$V_F = V_{EC}$	$I_F = 400\text{ A}$	$T_j = 25^\circ\text{C}$		1.3	1.53	V
	$V_{GE} = 0\text{ V}$ chip	$T_j = 150^\circ\text{C}$		1.3	1.5	V
V_{F0}		$T_j = 25^\circ\text{C}$	0.9	1	1.1	V
		$T_j = 150^\circ\text{C}$	0.75	0.85	0.95	V
r_F		$T_j = 25^\circ\text{C}$	0.7	0.9	1.1	m Ω
		$T_j = 150^\circ\text{C}$	1.0	1.2	1.4	m Ω
I_{RRM}	$I_F = 400\text{ A}$	$T_j = 150^\circ\text{C}$		250		A
Q_{rr}	$di/dt_{off} = 3700\text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$		47		μC
E_{rr}	$V_{GE} = -8\text{ V}$	$T_j = 150^\circ\text{C}$		10		mJ
	$V_{CC} = 300\text{ V}$	$T_j = 150^\circ\text{C}$				
$R_{th(j-c)}$	per diode				0.15	K/W
Module						
L_{CE}				18		nH
R_{CC+EE}	res., terminal-chip	$T_C = 25^\circ\text{C}$		0.7		m Ω
		$T_C = 125^\circ\text{C}$		1		m Ω
$R_{th(c-s)}$	per module			0.045		K/W
M_s	to heat sink (M5)		3		5	Nm
M_t		to terminals (M6)	2.5		5	Nm
						Nm
w					250	g
Temperatur Sensor						
R_{100}	$T_C=100^\circ\text{C}$ ($R_{25}=5\text{ k}\Omega$)			$493 \pm 5\%$		Ω
$B_{100/125}$	$R(T)=R_{100}\exp[B_{100/125}(1/T-1/T_{100})]$; $T[K]$;			$3550 \pm 2\%$		K

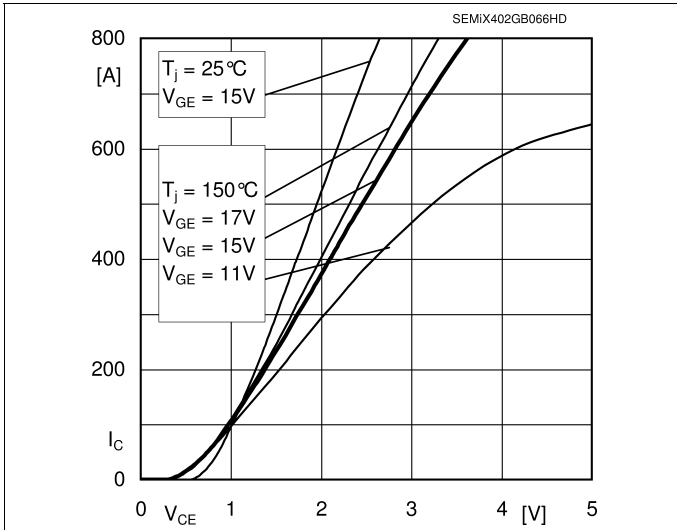


Fig. 1: Typ. output characteristic, inclusive R_{CC+EE}

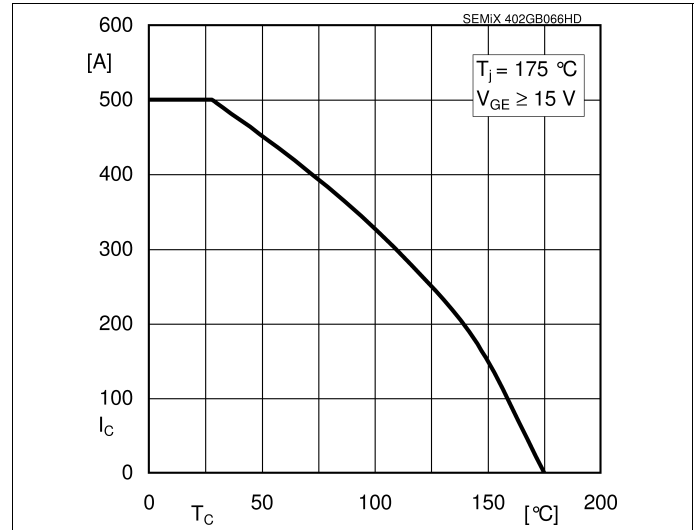


Fig. 2: Rated current vs. temperature $I_C = f(T_C)$

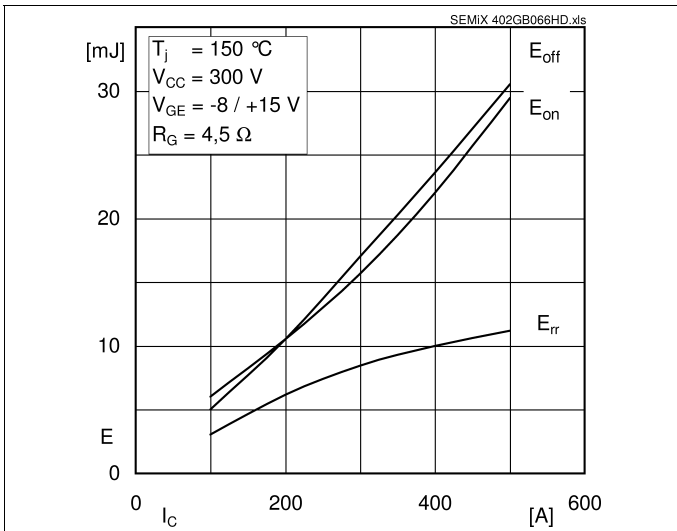


Fig. 3: Typ. turn-on /-off energy = $f(I_C)$

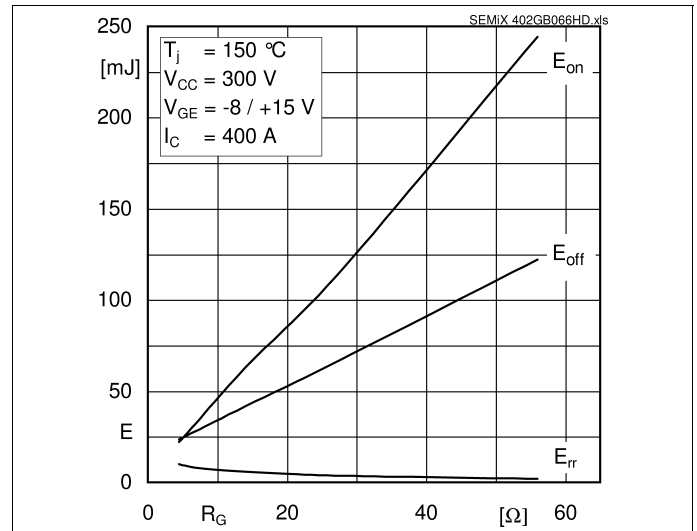


Fig. 4: Typ. turn-on /-off energy = $f(R_G)$

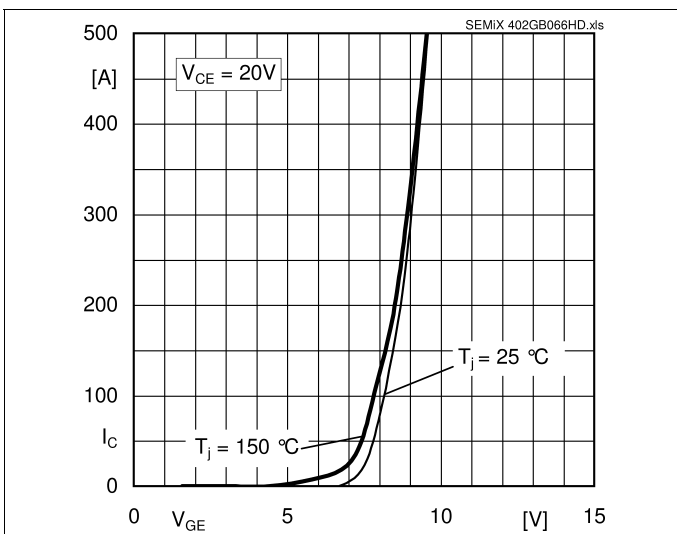


Fig. 5: Typ. transfer characteristic

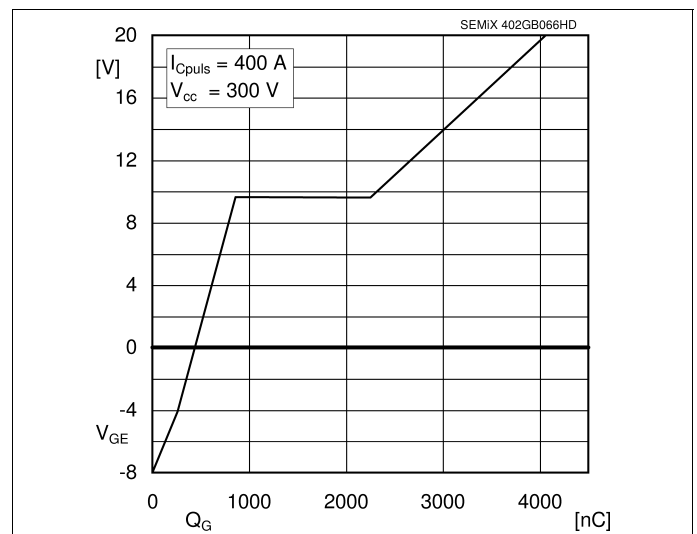
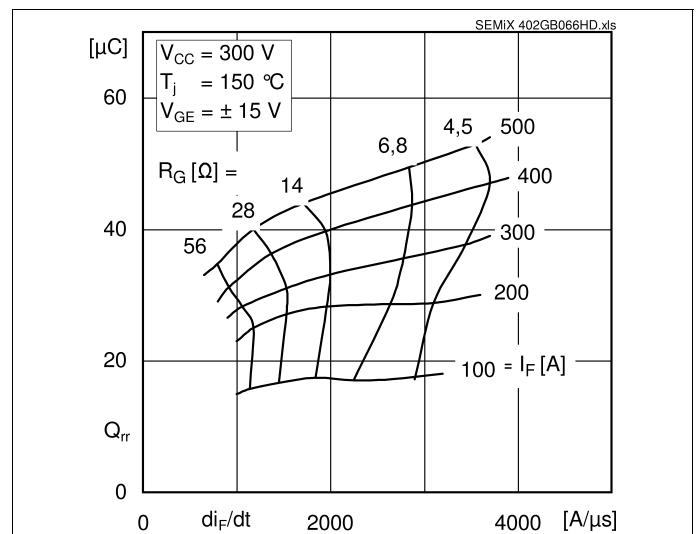
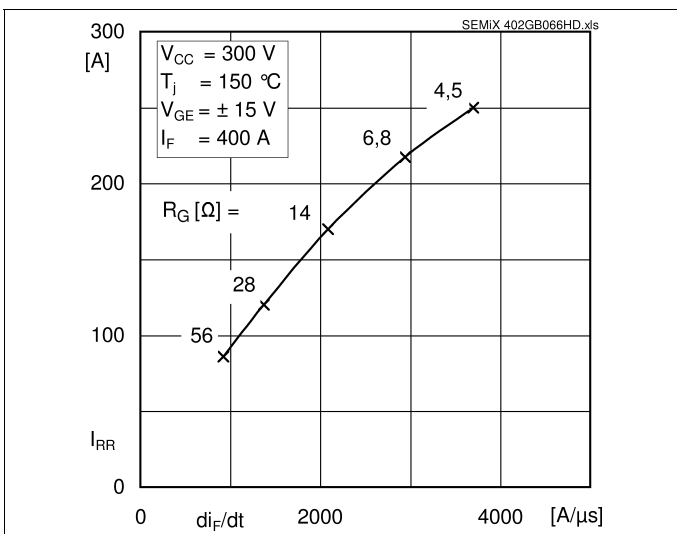
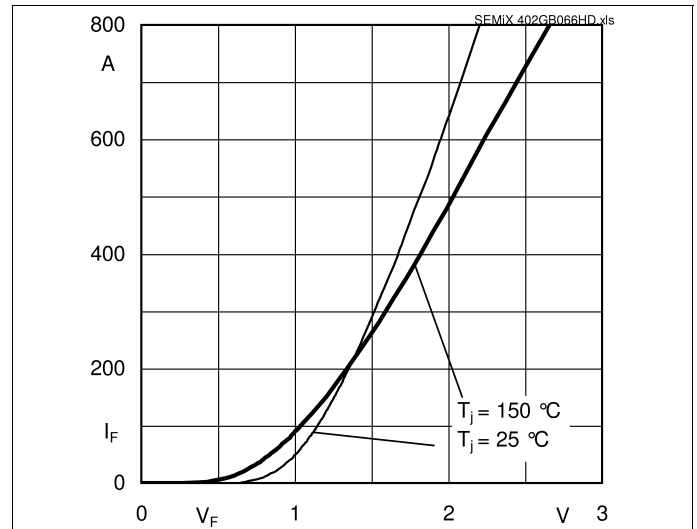
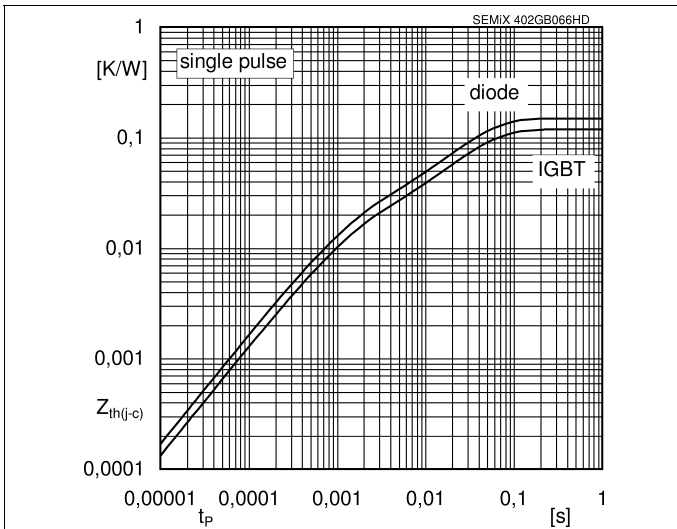
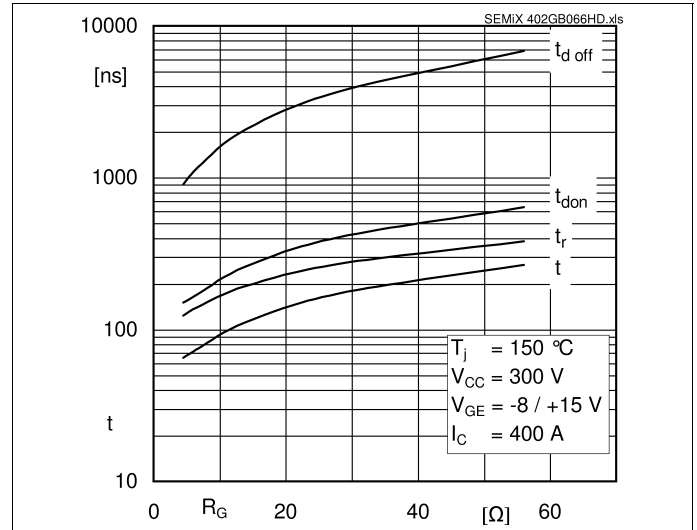
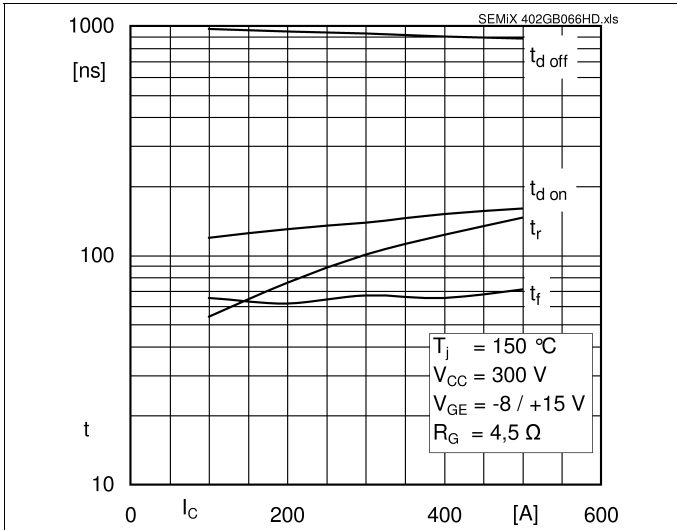


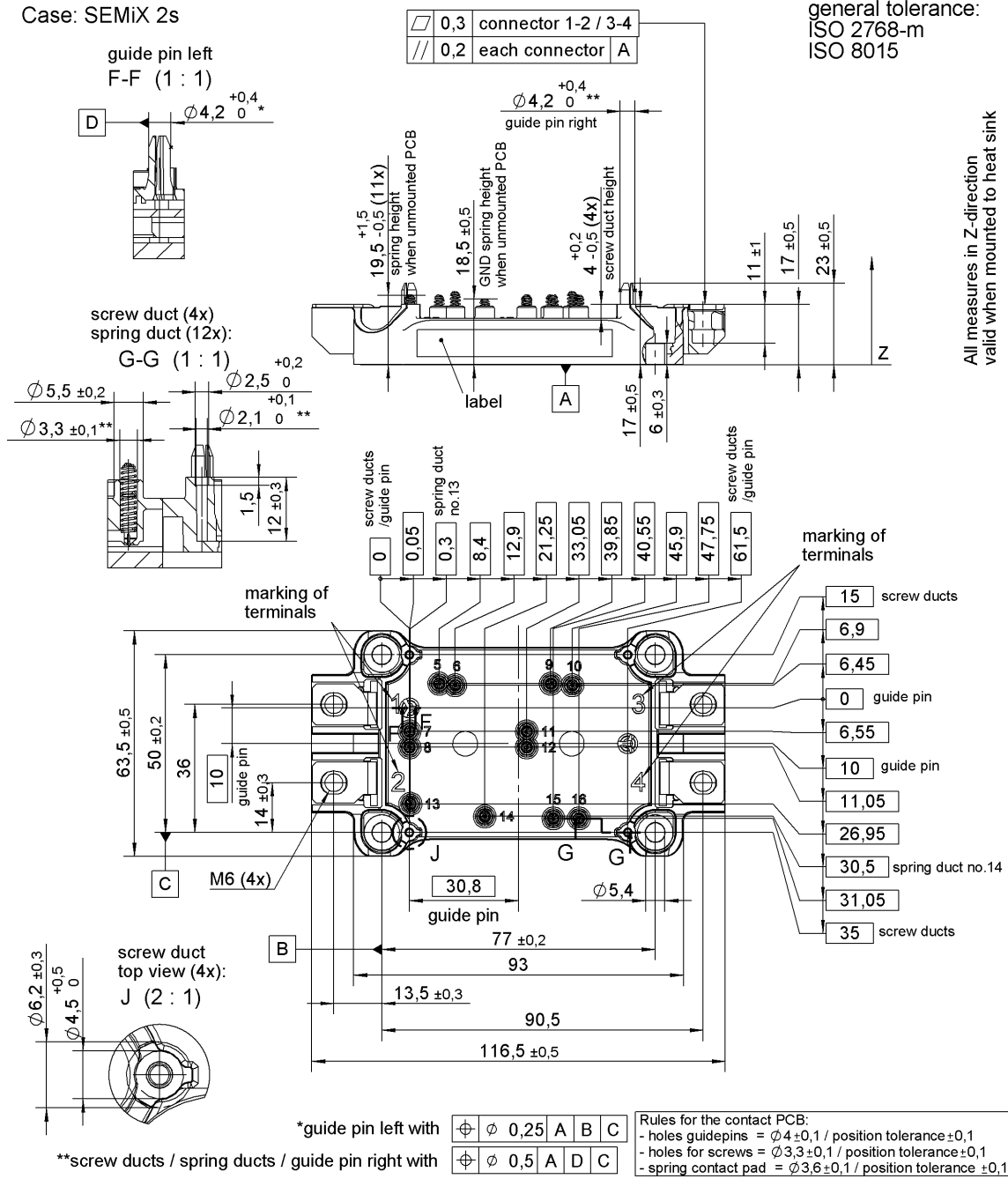
Fig. 6: Typ. gate charge characteristic



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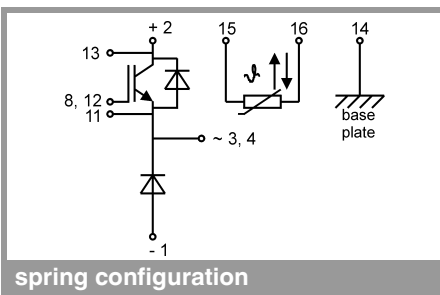
Case: SEMiX 2s

general tolerance:
ISO 2768-m
ISO 8015



All measures in Z-direction
valid when mounted to heat sink

SEMIX 2s



This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX

* The specifications of our components may not be considered as an assurance of component characteristics. Components have to be tested for the respective application. Adjustments may be necessary. The use of SEMIKRON products in life support appliances and systems is subject to prior specification and written approval by SEMIKRON. We therefore strongly recommend prior consultation of our staff.